


<b>Search Notes</b> 	<b>Application/Control No.</b> 10688763	<b>Applicant(s)/Patent Under Reexamination</b> YIP ET AL.
	<b>Examiner</b> Wang, Ben C	<b>Art Unit</b> 2196

SEARCHED			
Class	Subclass	Date	Examiner
717	125	11/27/2006	Ben C. Wang
345	581-681	11/27/2006	Ben C. Wang

SEARCH NOTES		
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Google, IEEE, ACM Databases Search	11/27/2006	Ben C. Wang

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